

November 2001

FDP2670/FDB2670

200V N-Channel PowerTrench® MOSFET

General Description

This N-Channel MOSFET has been designed specifically for switching on the primary side in the isolated DC/DC converter application. Any application requiring a 200V MOSFETs with low on-resistance and fast switching will benefit.

These MOSFETs feature faster switching and lower gate charge than other MOSFETs with comparable $RDS_{(\text{ON})}$ specifications.

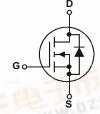
The result is a MOSFET that is easy and safer to drive (even at very high frequencies), and DC/DC power supply designs with higher overall efficiency.

Features

- 19 A, 200 V. $R_{DS(ON)} = 130 \text{ m}\Omega$ @ $V_{GS} = 10 \text{ V}$
- Low gate charge (27 nC typical)
- · Fast switching speed
- High performance trench technology for extremely low R_{DS(ON)}
- High power and current handling capability







Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter	EV(6) :	Ratings	Units
V _{DSS}	Drain-Source Voltage	A.	200	V
V _{GSS}	Gate-Source Voltage		± 20	V
I _D	Drain Current - Continuous	(Note 1)	19	А
	- Pulsed	(Note 1)	40	Α
P _D	Total Power Dissipation @ T _C = 25°C		93	W
	Derate above 25°C		0.63	W°/C
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	3.2	V/ns
T _J , T _{STG}	Operating and Storage Junction Temperature Range		−65 to +175	°C

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FDB Series

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	1.6	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDB2670	FDB2670	13"	24mm	800 units
FDP2670	FDP2670	Tube	n/a	45 units



Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-Sc	ource Avalanche Ratings (Note	1)	-1		I	
W _{DSS}	Single Pulse Drain-Source Avalanche Energy	$V_{DD} = 100 \text{ V}, \qquad I_{D} = 10 \text{ A}$			375	mJ
I _{AR}	Maximum Drain-Source Avalanche Current				10	Α
Off Char	acteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$	200			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I_D = 250 μA, Referenced to 25°C		241		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 160 \text{ V}, V_{GS} = 0 \text{ V}$			1	μΑ
I _{GSSF}	Gate-Body Leakage, Forward	$V_{GS} = 20 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
I _{GSSR}	Gate-Body Leakage, Reverse	$V_{GS} = -20 \text{ V}$ $V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	2	4	4.5	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		-9		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	$V_{GS} = 10 \text{ V}, \qquad I_D = 10 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}, T_J = 125 ^{\circ}\text{C}$		98 205	130 285	mΩ
I _{D(on)}	On-State Drain Current	$V_{GS} = 10 \text{ V}, \qquad V_{DS} = 10 \text{ V}$	20			Α
g FS	Forward Transconductance	$V_{DS} = 10 \text{ V}, \qquad I_{D} = 10 \text{ A}$		24		S
Dynamic	Characteristics					
C _{iss}	Input Capacitance	$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V},$		1320		pF
C _{oss}	Output Capacitance	f = 1.0 MHz		71		pF
C _{rss}	Reverse Transfer Capacitance			24		pF
Switchin	g Characteristics (Note 2)		•	•	•	•
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 100 \text{ V}, \qquad I_{D} = 1 \text{ A},$		14	25	ns
t _r	Turn-On Rise Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		5	10	ns
t _{d(off)}	Turn-Off Delay Time			26	41	ns
t _f	Turn-Off Fall Time			23	37	ns
Qg	Total Gate Charge	$V_{DS} = 100 \text{ V}, \qquad I_{D} = 10 \text{ A},$		27	38	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V		7		nC
Q_{gd}	Gate-Drain Charge]		10		nC
Drain-Se	ource Diode Characteristics	and Maximum Ratings				
Is	Maximum Continuous Drain–Source				19	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 10 \text{ A}$ (Note 2)		0.8	1.3	V

Notes:

- 1. Calculated continuous current based on maximum allowable junction temperature.
- 2. Pulse Test: Pulse Width < 300 μ s, Duty Cycle < 2.0%
- 3. $I_{SD} \leq 3A, \, di/dt \leq 100A/\mu s, \, V_{DD} \leq BV_{DSS}, \, Starting \, T_J = 25^{\circ}C$

Typical Characteristics

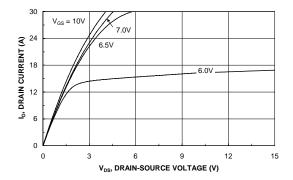


Figure 1. On-Region Characteristics.

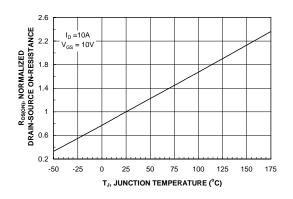


Figure 3. On-Resistance Variation with Temperature.

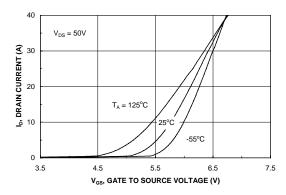


Figure 5. Transfer Characteristics.

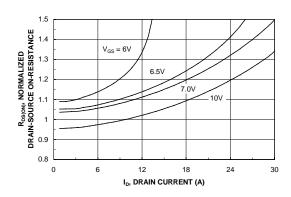


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

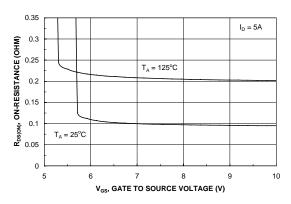


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

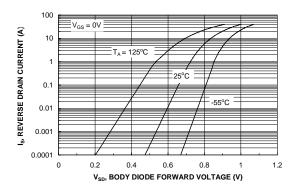
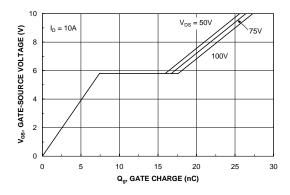


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



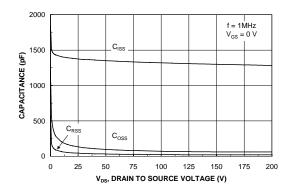


Figure 7. Gate Charge Characteristics.

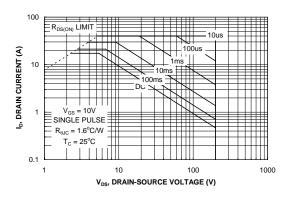


Figure 8. Capacitance Characteristics.

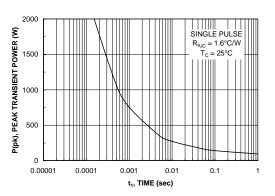


Figure 9. Maximum Safe Operating Area.



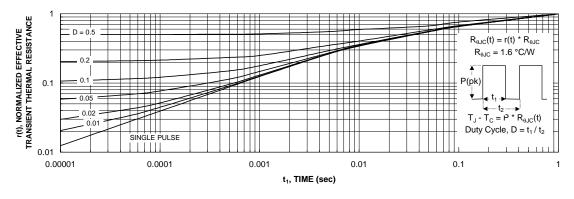


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1. Transient thermal response will change depending on the circuit board design.

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